

MOS FIELD EFFECT TRANSISTOR 2SJ626

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The 2SJ626 is a switching device which can be driven directly by a 4.0 V power source.

The 2SJ626 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- 4.0 V drive available
- · Low on-state resistance

 $R_{DS(on)1} = 388 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -10 \text{ V, Id} = -1.0 \text{ A)}$

 $R_{DS(on)2} = 514 \text{ m}\Omega$ MAX. (Vgs = -4.5 V, ID = -1.0 A)

RDS(on)3 = 556 m Ω MAX. (VGS = -4.0 V, ID = -1.0 A)

ORDERING INFORMATION

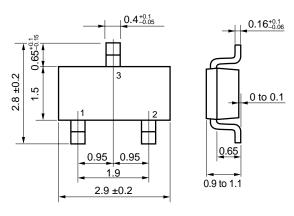
PART NUMBER	PACKAGE
2SJ626	SC-96 (Mini Mold Thin Type)

Marking: XN

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

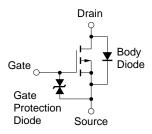
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Drain to Source Voltage (Vgs = 0 V)	VDSS	-60	V
Gate to Source Voltage (Vps = 0 V)	Vgss	∓20	V
Drain Current (DC) (T _A = 25°C)	ID(DC)	∓1.5	Α
Drain Current (pulse) Note1	ID(pulse)	∓6.0	Α
Total Power Dissipation	P _{T1}	0.2	W
Total Power Dissipation Note2	P _{T2}	1.25	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

PACKAGE DRAWING (Unit: mm)



- 1 : Gate 2 : Source
- 3 : Drain

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Mounted on FR-4 board, $t \le 5$ sec.

Remark The di

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

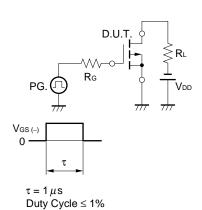
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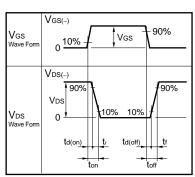


ELECTRICAL CHARACTERISTICS (TA = 25°C)

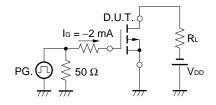
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	V _{DS} = -60 V, V _{GS} = 0 V			-1.0	μΑ
Gate Leakage Current	Igss	V _{GS} = ∓20 V, V _{DS} = 0 V			∓10	μΑ
Gate to Source Cut-off Voltage	V _{GS(off)}	$V_{DS} = -10 \text{ V}, I_{D} = -1.0 \text{ mA}$	-1.5	-2.1	-2.5	V
Forward Transfer Admittance	yfs	V _{DS} = -10 V, I _D = -1.0 A	1.0	2.5		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = -10 V, ID = -1.0 A		310	388	mΩ
	RDS(on)2	Vgs = -4.5 V, ID = -1.0 A		385	514	mΩ
	RDS(on)3	Vgs = -4.0 V, ID = -1.0 A		417	556	mΩ
Input Capacitance	Ciss	V _{DS} = −10 V		255		pF
Output Capacitance	Coss	VGS = 0 V		45		pF
Reverse Transfer Capacitance	Crss	f = 1.0 MHz		17		pF
Turn-on Delay Time	t _{d(on)}	$V_{DD} = -30 \text{ V}, I_{D} = -1.0 \text{ A}$		17		ns
Rise Time	tr	V _G S = −10 V		29		ns
Turn-off Delay Time	t _{d(off)}	$R_G = 10 \Omega$		92		ns
Fall Time	t _f			65		ns
Total Gate Charge	Q _G	V _{DD} = -48 V		8.2		nC
Gate to Source Charge	Qgs	V _{GS} = −10 V		1.3		nC
Gate to Drain Charge	Q _{GD}	I _D = -1.5 A		2.2		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 1.5 A, VGS = 0 V		0.86		V

TEST CIRCUIT 1 SWITCHING TIME



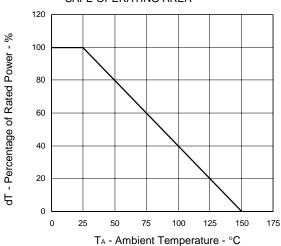


TEST CIRCUIT 2 GATE CHARGE

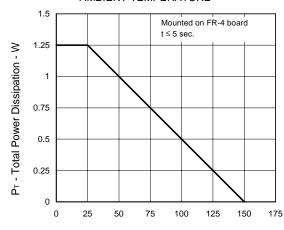


TYPICAL CHARACTERISTICS (TA = 25°C)

DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA

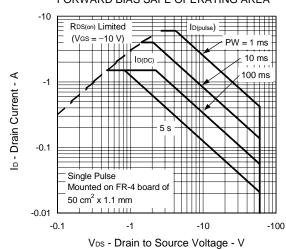


TOTAL POWER DISSIPATION vs. AMBIENT TEMPERATURE

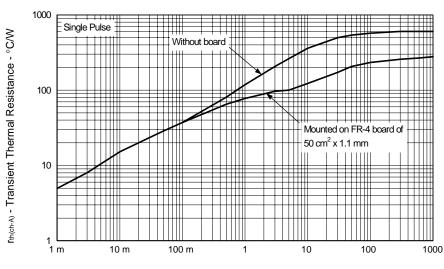


T_A - Ambient Temperature - °C

FORWARD BIAS SAFE OPERATING AREA



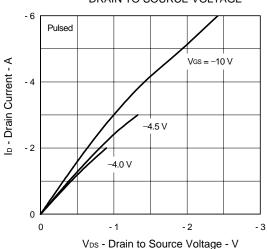
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



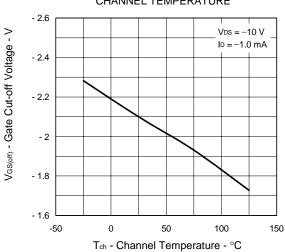
PW - Pulse Width - s

3

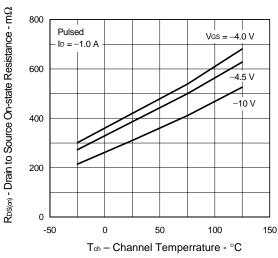
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



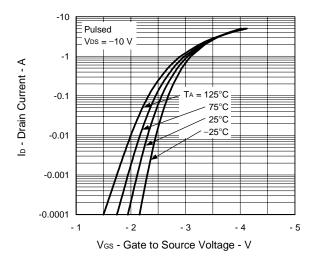
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



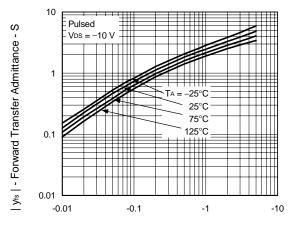
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



FORWARD TRANSFER CHARACTERISTICS

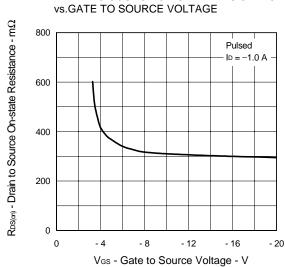


FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

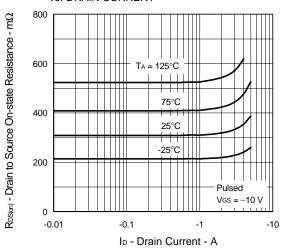


In - Drain Current - A

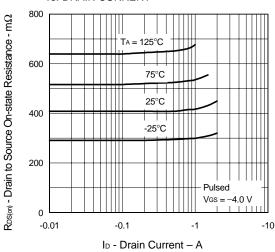
DRAIN TO SOURCE ON-STATE RESISTANCE



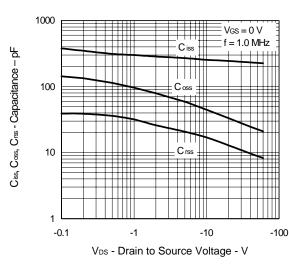
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



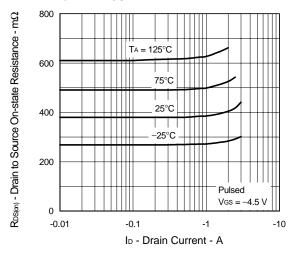
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



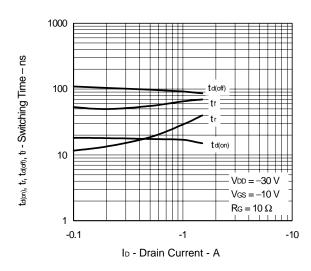
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



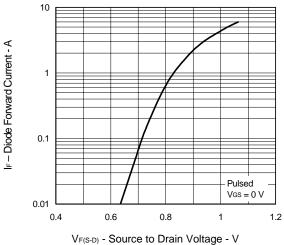
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



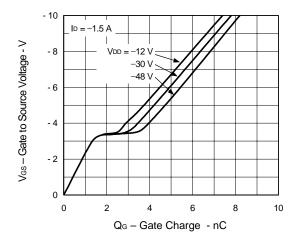
SWITCHING CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE



DYNAMIC INPUT/OUTPUT CHARACTERISTICS



[MEMO]

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